

Notic of R ferences Cited

Application/Control No.

10/053,970

Applicant(s)/Patent Under
Reexamination
JACOB ET AL

Examiner

Viet Q Nguyen

Art Unit

2818

Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2001/0055229	12-2001	Koike, Hiroki	365/200
	B	US-6,046,926	04-2000	Tanaka et al.	365/145
	C	US-2002/0085406	07-2002	McClure, David C.	365/145
	D	US-2002/0093847	07-2002	Tada, Yoshihiro	365/145
	E	US-6,512,686	01-2003	Miyamoto, Yasuo	365/145
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Viet Q. Nguyen Primary Examiner
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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